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Surface chemical analysis — X-ray photoelectron spectroscopy — Description of selected instrumental performance parameters

*Analyse chimique des surfaces — Spectroscopie de
photoélectrons X — Description de certains paramètres relatifs à
la performance instrumentale*



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Foreword

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Introduction

X-ray photoelectron spectrometers are produced by many manufacturers throughout the world. While the basic principle of the XPS analytical method in each instrument is the same, the specific designs of the instruments and the way that performance specifications are provided differ widely. As a result, it is often difficult to compare the performance of instruments from one manufacturer with those from another. This International Standard provides a basic list of items devised to enable all X-ray photoelectron spectrometers to be described in a common manner. This International Standard is not intended to replace the manufacturer's specification, which may extend to 30 or more pages. It is intended that, where certain items are defined in that specification, there is an agreed and defined meaning to that item.